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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	133MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (2), 10/100Mbps (2)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	3.3V
Operating Temperature	-40°C ~ 100°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc880czp133

Table 3. Operating Temperatures

Rating	Symbol	Value	Unit
Temperature[1] (standard)	$T_{A(min)}$	0	°C
	$T_{J(max)}$	95	°C
Temperature (extended)	$T_{A(min)}$	–40	°C
	$T_{J(max)}$	100	°C

1 Minimum temperatures are guaranteed as ambient temperature, T_A. Maximum temperatures are guaranteed as junction temperature, T_J.

This device contains circuitry protecting against damage due to high-static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for example, either GND or V_{DD}).

4 Thermal Characteristics

Table 4 shows the thermal characteristics for the MPC885/MPC880.

Table 4. MPC885/MPC880 Thermal Resistance Data

Rating	Environment		Symbol	Value	Unit
Junction-to-ambient[1]	Natural convection	Single-layer board (1s)	$R_{\theta JA}$[2]	37	°C/W
		Four-layer board (2s2p)	$R_{\theta JMA}$[3]	25	
	Airflow (200 ft/min)	Single-layer board (1s)	$R_{\theta JMA}$[3]	30	
		Four-layer board (2s2p)	$R_{\theta JMA}$[3]	22	
Junction-to-board[4]	—	—	$R_{\theta JB}$	17	
Junction-to-case [5]	—	—	$R_{\theta JC}$	10	
Junction-to-package top[6]	Natural convection	—	Ψ_{JT}	2	
	Airflow (200 ft/min)	—	Ψ_{JT}	2	

1 Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.

2 Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.

3 Per JEDEC JESD51-6 with the board horizontal.

4 Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.

5 Indicates the average thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the cold plate temperature used for the case temperature. For exposed pad packages where the pad would be expected to be soldered, junction-to-case thermal resistance is a simulated value from the junction to the exposed pad without contact resistance.

6 Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

$R_{\theta JB}$ = junction-to-board thermal resistance (ºC/W)

T_B = board temperature (ºC)

P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and vias attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

Ψ_{JT} = thermal characterization parameter

T_T = thermocouple temperature on top of package

P_D = power dissipation in package

The thermal characterization parameter is measured per the JESD51-2 specification published by JEDEC using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over about 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by the cooling effects of the thermocouple wire.

Table 9. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B16b	$\overline{BB}$, $\overline{BG}$, $\overline{BR}$, valid to CLKOUT (setup time)[2] (4MIN = 0.00 × B1 + 0.00)	4.00	—	4.00	—	4.00	—	4.00	—	ns
B17	CLKOUT to $\overline{TA}$, $\overline{TEA}$, $\overline{BI}$, $\overline{BB}$, $\overline{BG}$, $\overline{BR}$ valid (hold time) (MIN = 0.00 × B1 + 1.00[3])	1.00	—	1.00	—	2.00	—	2.00	—	ns
B17a	CLKOUT to $\overline{KR}$, $\overline{RETRY}$, $\overline{CR}$ valid (hold time) (MIN = 0.00 × B1 + 2.00)	2.00	—	2.00	—	2.00	—	2.00	—	ns
B18	D(0:31) valid to CLKOUT rising edge (setup time)[4] (MIN = 0.00 × B1 + 6.00)	6.00	—	6.00	—	6.00	—	6.00	—	ns
B19	CLKOUT rising edge to D(0:31) valid (hold time)[4] (MIN = 0.00 × B1 + 1.00[5])	1.00	—	1.00	—	2.00	—	2.00	—	ns
B20	D(0:31) valid to CLKOUT falling edge (setup time)[6] (MIN = 0.00 × B1 + 4.00)	4.00	—	4.00	—	4.00	—	4.00	—	ns
B21	CLKOUT falling edge to D(0:31) valid (hold time)[6] (MIN = 0.00 × B1 + 2.00)	2.00	—	2.00	—	2.00	—	2.00	—	ns
B22	CLKOUT rising edge to $\overline{CS}$ asserted GPCM ACS = 00 (MAX = 0.25 × B1 + 6.3)	7.60	13.80	6.30	12.50	3.80	10.00	3.13	9.43	ns
B22a	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = [0 or 1] (MAX = 0.00 × B1 + 8.00)	—	8.00	—	8.00	—	8.00	—	8.00	ns
B22b	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = [0 or 1], EBDF = 0 (MAX = 0.25 × B1 + 6.3)	7.60	13.80	6.30	12.50	3.80	10.00	3.13	9.43	ns
B22c	CLKOUT falling edge to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = [0 or 1], EBDF = 1 (MAX = 0.375 × B1 + 6.6)	10.90	18.00	10.90	16.00	5.20	12.30	4.69	10.93	ns
B23	CLKOUT rising edge to $\overline{CS}$ negated GPCM read access, GPCM write access ACS = 00 and CSNT = 0 (MAX = 0.00 × B1 + 8.00)	2.00	8.00	2.00	8.00	2.00	8.00	2.00	8.00	ns
B24	A(0:31) and BADDR(28:30) to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = 0 (MIN = 0.25 × B1 – 2.00)	5.60	—	4.30	—	1.80	—	1.13	—	ns
B24a	A(0:31) and BADDR(28:30) to $\overline{CS}$ asserted GPCM ACS = 11 TRLX = 0 (MIN = 0.50 × B1 – 2.00)	13.20	—	10.50	—	5.60	—	4.25	—	ns
B25	CLKOUT rising edge to $\overline{OE}$, $\overline{WE}$(0:3) asserted (MAX = 0.00 × B1 + 9.00)	—	9.00	—	9.00	—	9.00	—	9.00	ns
B26	CLKOUT rising edge to $\overline{OE}$ negated (MAX = 0.00 X B1 + 9.00)	2.00	9.00	2.00	9.00	2.00	9.00	2.00	9.00	ns
B27	A(0:31) and BADDR(28:30) to $\overline{CS}$ asserted GPCM ACS = 10, TRLX = 1 (MIN = 1.25 × B1 – 2.00)	35.90	—	29.30	—	16.90	—	13.60	—	ns

Table 9. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B27a	A(0:31) and BADDR(28:30) to $\overline{CS}$ asserted GPCM ACS = 11, TRLX = 1 (MIN = 1.50 × B1 – 2.00)	43.50	—	35.50	—	20.70	—	16.75	—	ns
B28	CLKOUT rising edge to $\overline{WE}$(0:3) negated GPCM write access CSNT = 0 (MAX = 0.00 × B1 + 9.00)	—	9.00	—	9.00	—	9.00	—	9.00	ns
B28a	CLKOUT falling edge to $\overline{WE}$(0:3) negated GPCM write access TRLX = 0, CSNT = 1, EBDF = 0 (MAX = 0.25 × B1 + 6.80)	7.60	14.30	6.30	13.00	3.80	10.50	3.13	9.93	ns
B28b	CLKOUT falling edge to $\overline{CS}$ negated GPCM write access TRLX = 0, CSNT = 1 ACS = 10 or ACS = 11, EBDF = 0 (MAX = 0.25 × B1 + 6.80)	—	14.30	—	13.00	—	10.50	—	9.93	ns
B28c	CLKOUT falling edge to $\overline{WE}$(0:3) negated GPCM write access TRLX = 0, CSNT = 1 write access TRLX = 0, CSNT = 1, EBDF = 1 (MAX = 0.375 × B1 + 6.6)	10.90	18.00	10.90	18.00	5.20	12.30	4.69	11.29	ns
B28d	CLKOUT falling edge to $\overline{CS}$ negated GPCM write access TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1 (MAX = 0.375 × B1 + 6.6)	—	18.00	—	18.00	—	12.30	—	11.30	ns
B29	$\overline{WE}$(0:3) negated to D(0:31) High-Z GPCM write access, CSNT = 0, EBDF = 0 (MIN = 0.25 × B1 – 2.00)	5.60	—	4.30	—	1.80	—	1.13	—	ns
B29a	$\overline{WE}$(0:3) negated to D(0:31) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 0 (MIN = 0.50 × B1 – 2.00)	13.20	—	10.50	—	5.60	—	4.25	—	ns
B29b	$\overline{CS}$ negated to D(0:31) High-Z GPCM write access, ACS = 00, TRLX = 0 & CSNT = 0 (MIN = 0.25 × B1 – 2.00)	5.60	—	4.30	—	1.80	—	1.13	—	ns
B29c	$\overline{CS}$ negated to D(0:31) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11 EBDF = 0 (MIN = 0.50 × B1 – 2.00)	13.20	—	10.50	—	5.60	—	4.25	—	ns
B29d	$\overline{WE}$(0:3) negated to D(0:31) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0 (MIN = 1.50 × B1 – 2.00)	43.50	—	35.50	—	20.70	—	16.75	—	ns
B29e	$\overline{CS}$ negated to D(0:31) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11 EBDF = 0 (MIN = 1.50 × B1 – 2.00)	43.50	—	35.50	—	20.70	—	16.75	—	ns
B29f	$\overline{WE}$(0:3) negated to D(0:31) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1 (MIN = 0.375 × B1 – 6.30)[7]	5.00	—	3.00	—	0.00	—	0.00	—	ns
B29g	$\overline{CS}$ negated to D(0:31) High-Z GPCM write access, TRLX = 0, CSNT = 1 ACS = 10 or ACS = 11, EBDF = 1 (MIN = 0.375 × B1 – 6.30)[7]	5.00	—	3.00	—	0.00	—	0.00	—	ns

Table 9. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		66 MHz		80 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B36	A(0:31), BADDR(28:30), and D(0:31) to $\overline{\text{GPL}}$ valid, as requested by control bit GxT4 in the corresponding word in the UPM (MIN = 0.25 × B1 – 2.00)	5.60	—	4.30	—	1.80	—	1.13	—	ns
B37	UPWAIT valid to CLKOUT falling edge[9] (MIN = 0.00 × B1 + 6.00)	6.00	—	6.00	—	6.00	—	6.00	—	ns
B38	CLKOUT falling edge to UPWAIT valid [9] (MIN = 0.00 × B1 + 1.00)	1.00	—	1.00	—	1.00	—	1.00	—	ns
B39	$\overline{\text{AS}}$ valid to CLKOUT rising edge[10] (MIN = 0.00 × B1 + 7.00)	7.00	—	7.00	—	7.00	—	7.00	—	ns
B40	A(0:31), TSIZ(0:1), RD/$\overline{\text{WR}}$, $\overline{\text{BURST}}$, valid to CLKOUT rising edge (MIN = 0.00 × B1 + 7.00)	7.00	—	7.00	—	7.00	—	7.00	—	ns
B41	$\overline{\text{TS}}$ valid to CLKOUT rising edge (setup time) (MIN = 0.00 × B1 + 7.00)	7.00	—	7.00	—	7.00	—	7.00	—	ns
B42	CLKOUT rising edge to $\overline{\text{TS}}$ valid (hold time) (MIN = 0.00 × B1 + 2.00)	2.00	—	2.00	—	2.00	—	2.00	—	ns
B43	$\overline{\text{AS}}$ negation to memory controller signals negation (MAX = TBD)	—	TBD	—	TBD	—	TBD	—	TBD	ns

1 For part speeds above 50 MHz, use 9.80 ns for B11a.

2 The timing required for $\overline{\text{BR}}$ input is relevant when the MPC885/MPC880 is selected to work with the internal bus arbiter. The timing for $\overline{\text{BG}}$ input is relevant when the MPC885/MPC880 is selected to work with the external bus arbiter.

3 For part speeds above 50 MHz, use 2 ns for B17.

4 The D(0:31) input timings B18 and B19 refer to the rising edge of the CLKOUT in which the $\overline{\text{TA}}$ input signal is asserted.

5 For part speeds above 50 MHz, use 2 ns for B19.

6 The D(0:31) input timings B20 and B21 refer to the falling edge of the CLKOUT. This timing is valid only for read accesses controlled by chip-selects under control of the user-programmable machine (UPM) in the memory controller, for data beats where DLT3 = 1 in the RAM words. (This is only the case where data is latched on the falling edge of CLKOUT.)

7 This formula applies to bus operation up to 50 MHz.

8 The timing B30 refers to $\overline{\text{CS}}$ when ACS = 00 and to $\overline{\text{CS}}$ and $\overline{\text{WE}}$(0:3) when CSNT = 0.

9 The signal UPWAIT is considered asynchronous to the CLKOUT and synchronized internally. The timings specified in B37 and B38 are specified to enable the freeze of the UPM output signals as described in Figure 21.

10 The $\overline{\text{AS}}$ signal is considered asynchronous to the CLKOUT. The timing B39 is specified in order to allow the behavior specified in Figure 24.

Figure 8 provides the timing for the synchronous output signals.

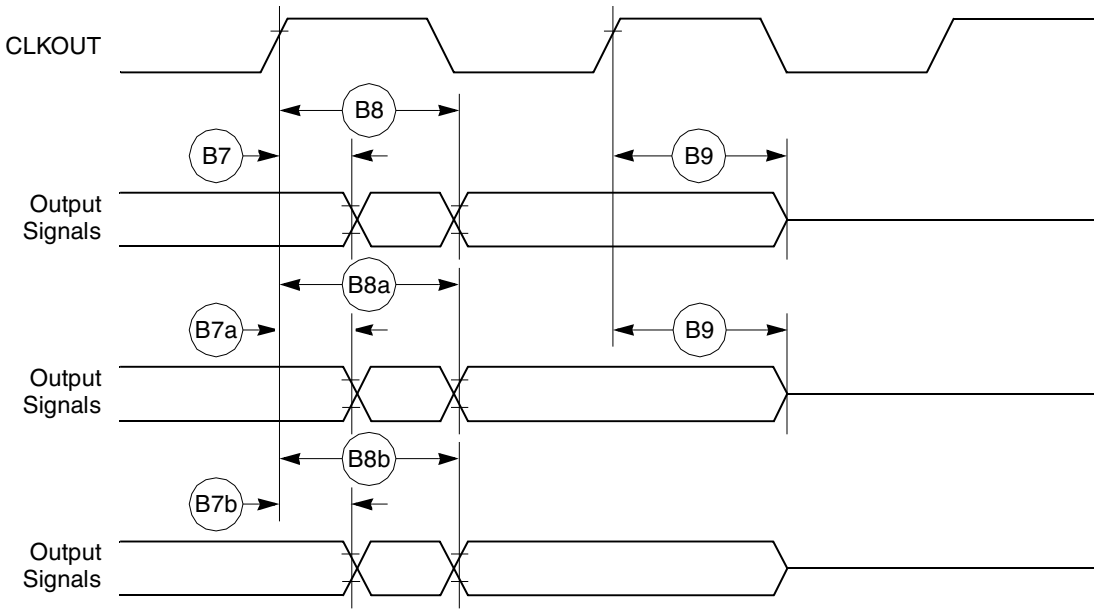


Figure 8. Synchronous Output Signals Timing

Figure 9 provides the timing for the synchronous active pull-up and open-drain output signals.

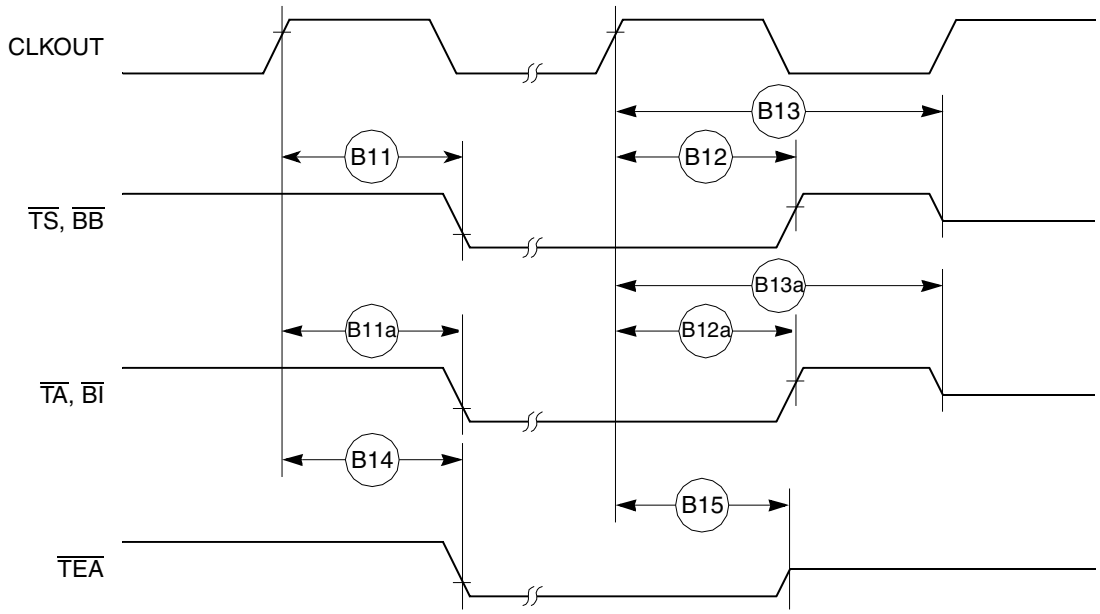


Figure 9. Synchronous Active Pull-Up Resistor and Open-Drain Outputs Signals Timing

Table 13 shows the debug port timing for the MPC885/MPC880.

Table 13. Debug Port Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
D61	DSCK cycle time	$3 \times T_{CLOCKOUT}$	—	—
D62	DSCK clock pulse width	$1.25 \times T_{CLOCKOUT}$	—	—
D63	DSCK rise and fall times	0.00	3.00	ns
D64	DSDI input data setup time	8.00	—	ns
D65	DSDI data hold time	5.00	—	ns
D66	DSCK low to DSDO data valid	0.00	15.00	ns
D67	DSCK low to DSDO invalid	0.00	2.00	ns

Figure 33 provides the input timing for the debug port clock.

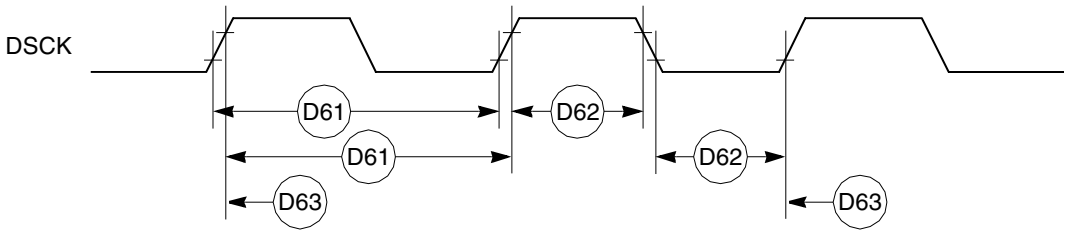


Figure 33. Debug Port Clock Input Timing

Figure 34 provides the timing for the debug port.

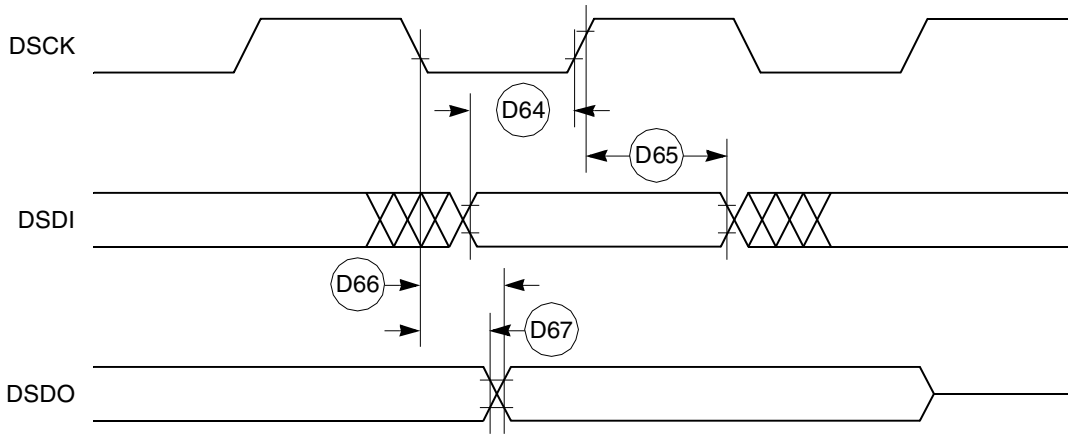


Figure 34. Debug Port Timings

12.3 IDMA Controller AC Electrical Specifications

Table 18 provides the IDMA controller timings as shown in Figure 48 tthrough Figure 51.

Table 18. IDMA Controller Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
40	$\overline{\text{DREQ}}$ setup time to clock high	7	—	ns
41	$\overline{\text{DREQ}}$ hold time from clock high [1]	TBD	—	ns
42	$\overline{\text{SDACK}}$ assertion delay from clock high	—	12	ns
43	$\overline{\text{SDACK}}$ negation delay from clock low	—	12	ns
44	$\overline{\text{SDACK}}$ negation delay from $\overline{\text{TA}}$ low	—	20	ns
45	$\overline{\text{SDACK}}$ negation delay from clock high	—	15	ns
46	$\overline{\text{TA}}$ assertion to rising edge of the clock setup time (applies to external $\overline{\text{TA}}$)	7	—	ns

[1] Applies to high-to-low mode (EDM = 1).

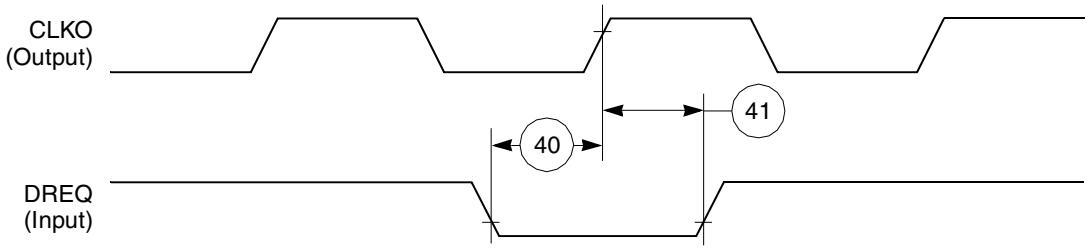


Figure 48. IDMA External Requests Timing Diagram

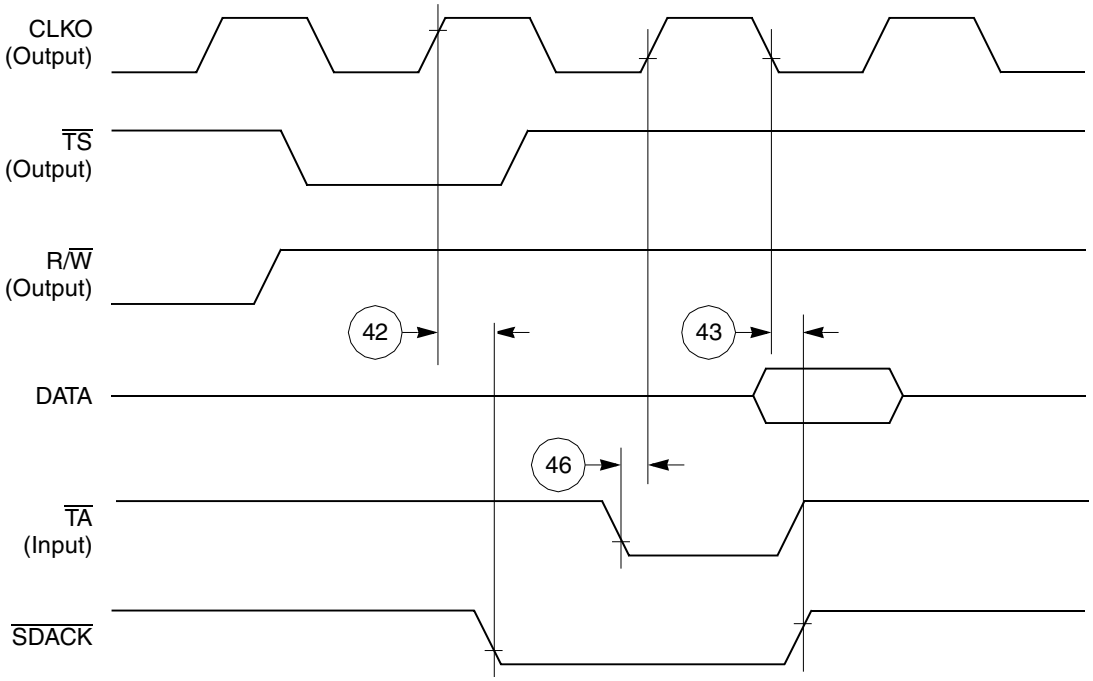


Figure 49. SDACK Timing Diagram—Peripheral Write, Externally-Generated TA

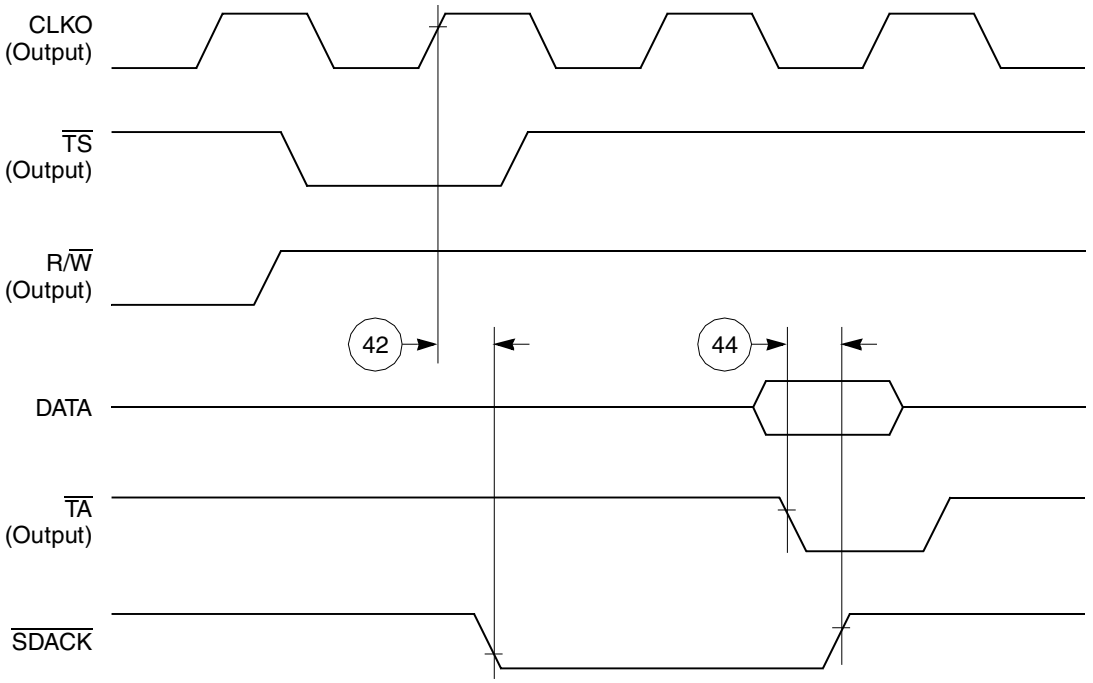


Figure 50. SDACK Timing Diagram—Peripheral Write, Internally-Generated TA

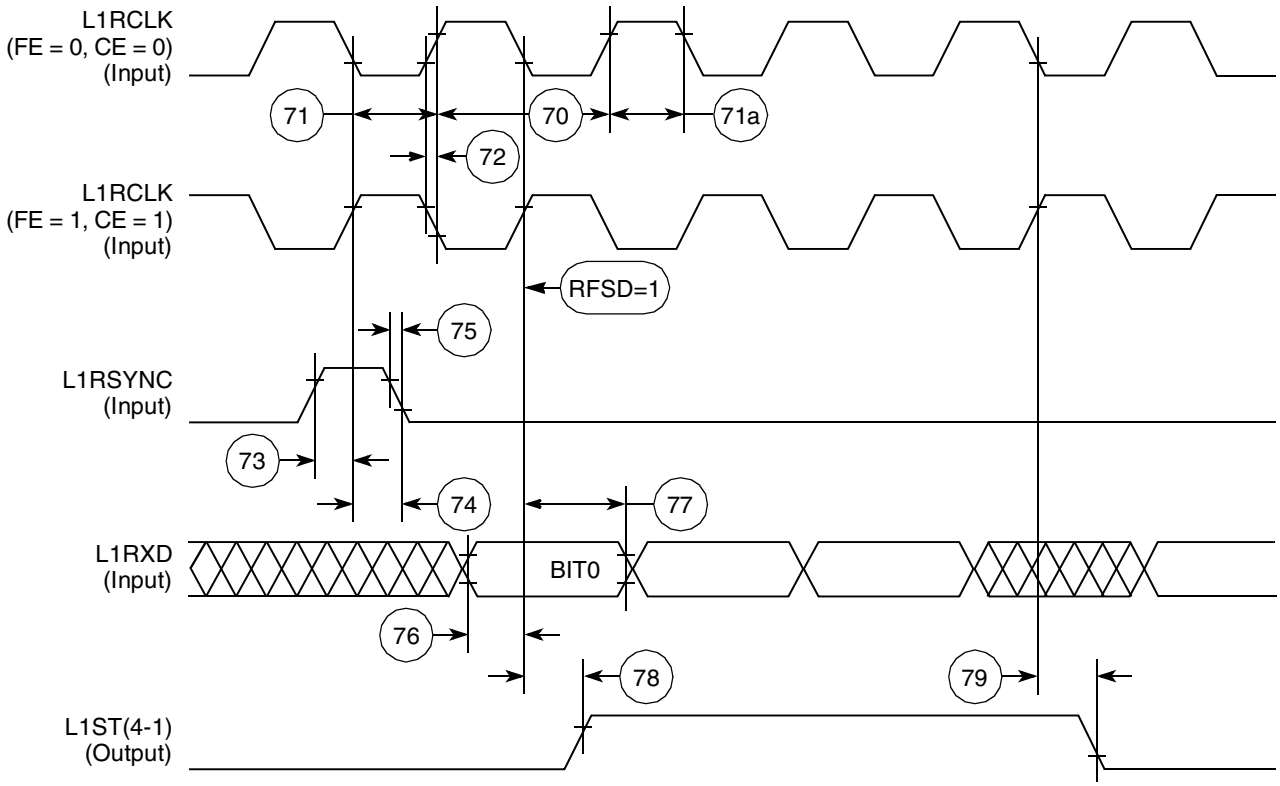


Figure 54. SI Receive Timing Diagram with Normal Clocking (DSC = 0)

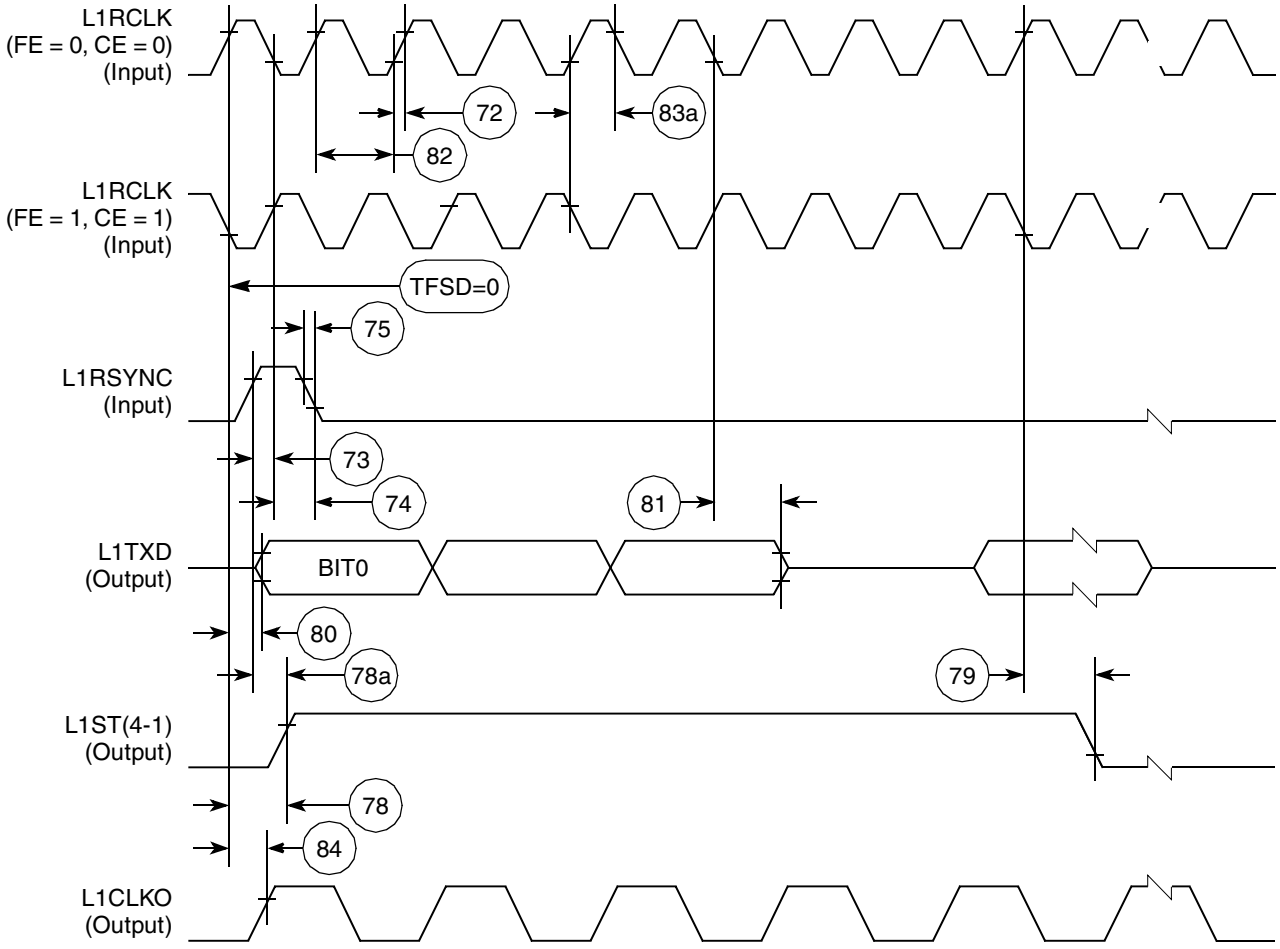


Figure 57. SI Transmit Timing with Double Speed Clocking (DSC = 1)

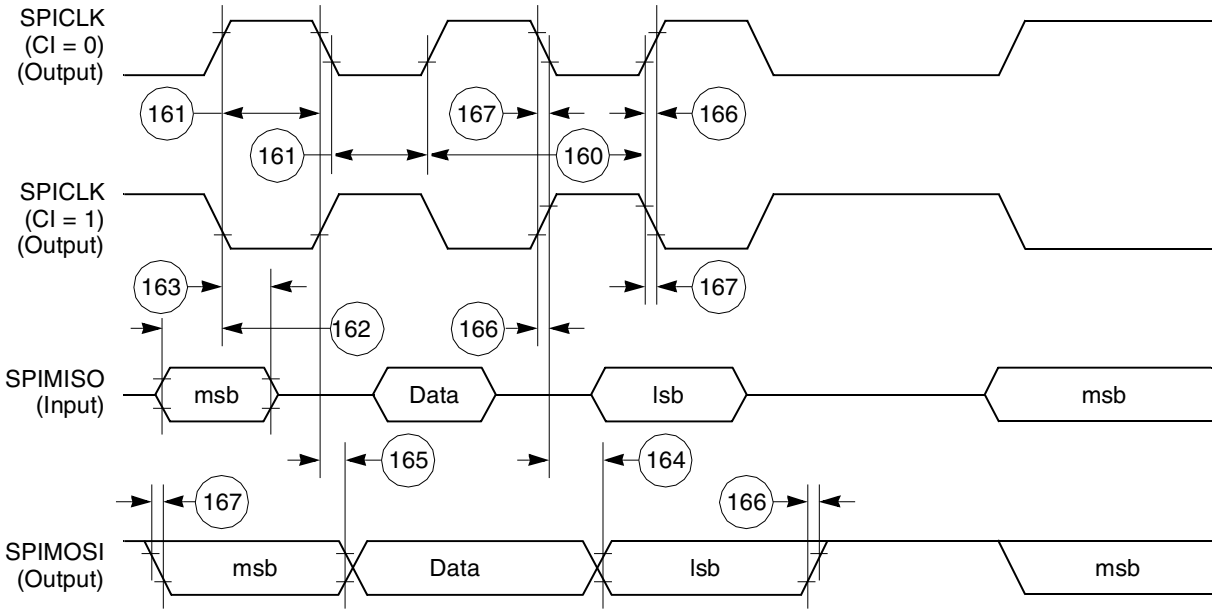


Figure 66. SPI Master (CP = 0) Timing Diagram

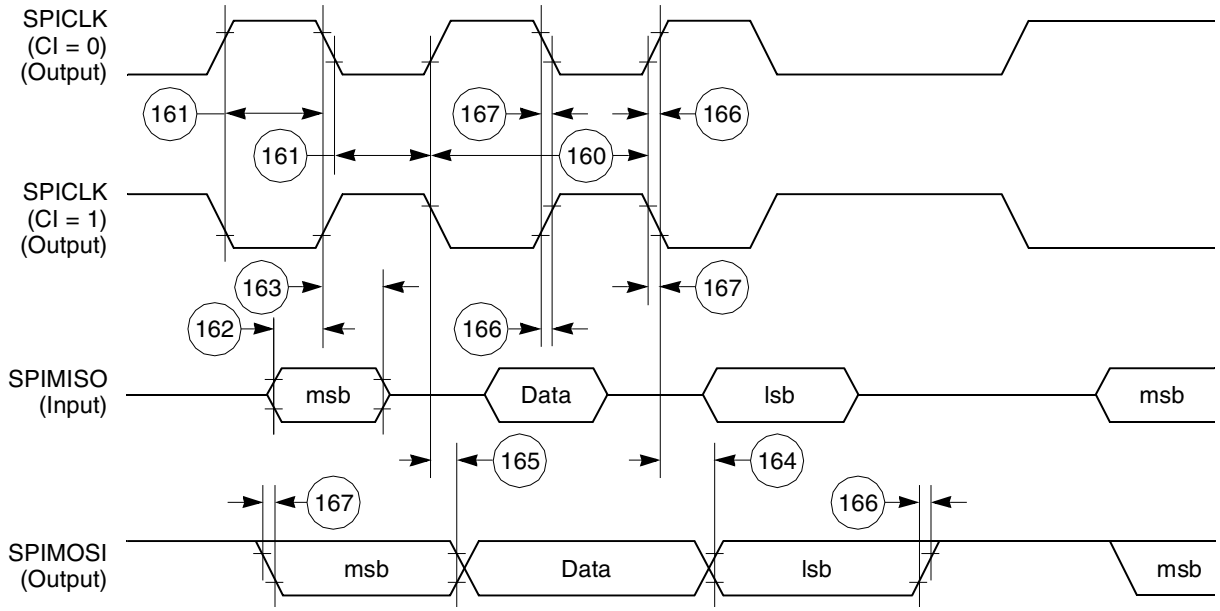


Figure 67. SPI Master (CP = 1) Timing Diagram

12.11 SPI Slave AC Electrical Specifications

Table 27 provides the SPI slave timings as shown in Figure 68 and Figure 69.

Table 27. SPI Slave Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
170	Slave cycle time	2	—	t_{cyc}
171	Slave enable lead time	15	—	ns
172	Slave enable lag time	15	—	ns
173	Slave clock (SPICLK) high or low time	1	—	t_{cyc}
174	Slave sequential transfer delay (does not require deselect)	1	—	t_{cyc}
175	Slave data setup time (inputs)	20	—	ns
176	Slave data hold time (inputs)	20	—	ns
177	Slave access time	—	50	ns

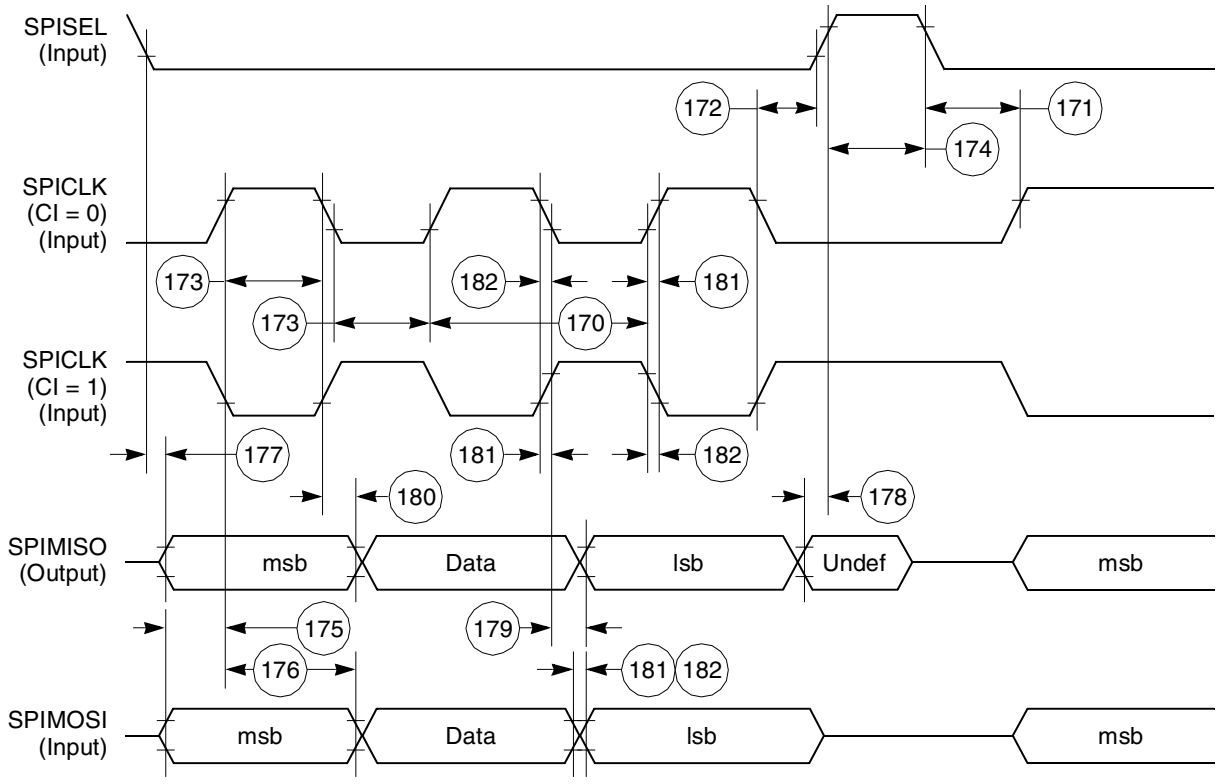


Figure 68. SPI Slave (CP = 0) Timing Diagram

Table 28. I²C Timing (SCL < 100 kHz) (continued)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	µs

1 SCL frequency is given by SCL = BRGCLK_frequency/((BRG register + 3) × pre_scaler × 2).
The ratio SyncClk/(BRGCLK/pre_scaler) must be greater or equal to 4/1.

Table 29 provides the I²C (SCL > 100 kHz) timings.

Table 29. I²C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master)[1]	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions	—	1/(2.2 × fSCL)	—	s
203	Low period of SCL	—	1/(2.2 × fSCL)	—	s
204	High period of SCL	—	1/(2.2 × fSCL)	—	s
205	Start condition setup time	—	1/(2.2 × fSCL)	—	s
206	Start condition hold time	—	1/(2.2 × fSCL)	—	s
207	Data hold time	—	0	—	s
208	Data setup time	—	1/(40 × fSCL)	—	s
209	SDL/SCL rise time	—	—	1/(10 × fSCL)	s
210	SDL/SCL fall time	—	—	1/(33 × fSCL)	s
211	Stop condition setup time	—	1/2(2.2 × fSCL)	—	s

1 SCL frequency is given by SCL = BrgClk_frequency/((BRG register + 3) × pre_scaler × 2).
The ratio SyncClk/(Brg_Clk/pre_scaler) must be greater or equal to 4/1.

Figure 70 shows the I²C bus timing.

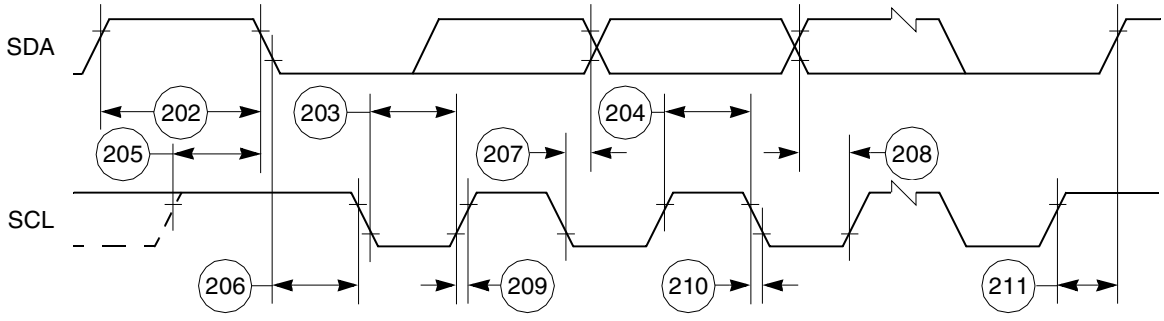


Figure 70. I²C Bus Timing Diagram

Figure 71 shows signal timings during UTOPIA receive operations.

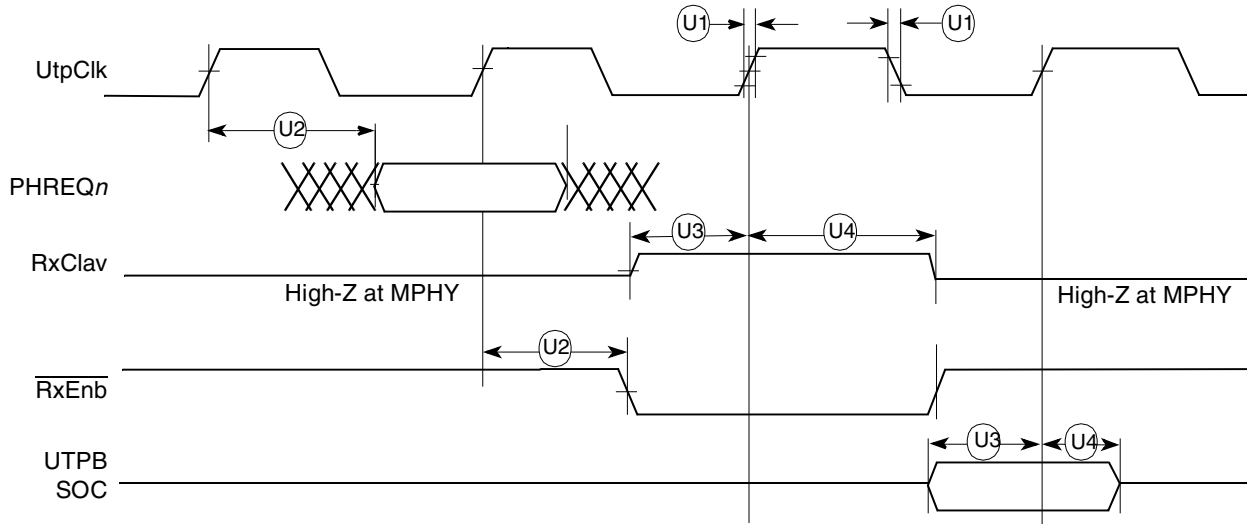


Figure 71. UTOPIA Receive Timing

Figure 72 shows signal timings during UTOPIA transmit operations.

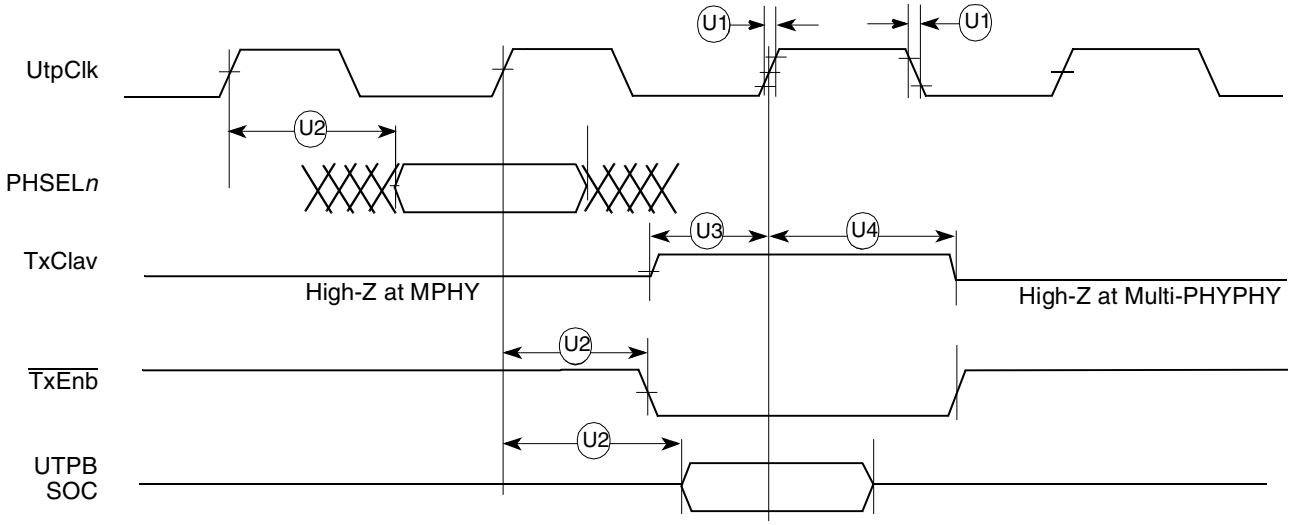


Figure 72. UTOPIA Transmit Timing

14 USB Electrical Characteristics

This section provides the AC timings for the USB interface.

14.1 USB Interface AC Timing Specifications

The USB Port uses the transmit clock on SCC1. Table 33 lists the USB interface timings.

Table 33. USB Interface AC Timing Specifications

Name	Characteristic	All Frequencies		Unit
		Min	Max	
US1	USBCLK frequency of operation[1] Low speed Full speed	 6 48		 MHz MHz
US4	USBCLK duty cycle (measured at 1.5 V)	45	55	%

[1] USBCLK accuracy should be ±500 ppm or better. USBCLK may be stopped to conserve power.

15 FEC Electrical Characteristics

This section provides the AC electrical specifications for the fast Ethernet controller (FEC). Note that the timing specifications for the MII signals are independent of system clock frequency (part speed designation). Also, MII signals use TTL signal levels compatible with devices operating at either 5.0 or 3.3 V.

15.1 MII and Reduced MII Receive Signal Timing

The receiver functions correctly up to a MII_RX_CLK maximum frequency of 25 MHz + 1%. The reduced MII (RMII) receiver functions correctly up to a RMII_REFCLK maximum frequency of 50 MHz + 1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_RX_CLK frequency – 1%.

Table 34 provides information on the MII and RMII receive signal timing.

Table 34. MII Receive Signal Timing

Num	Characteristic	Min	Max	Unit
M1	MII_RXD[3:0], MII_RX_DV, MII_RX_ERR to MII_RX_CLK setup	5	—	ns
M2	MII_RX_CLK to MII_RXD[3:0], MII_RX_DV, MII_RX_ER hold	5	—	ns
M3	MII_RX_CLK pulse width high	35%	65%	MII_RX_CLK period
M4	MII_RX_CLK pulse width low	35%	65%	MII_RX_CLK period
M1_RMII	RMII_RXD[1:0], RMII_CRS_DV, RMII_RX_ERR to RMII_REFCLK setup	4	—	ns
M2_RMII	RMII_REFCLK to RMII_RXD[1:0], RMII_CRS_DV, RMII_RX_ERR hold	2	—	ns

16 Mechanical Data and Ordering Information

Table 38 identifies the available packages and operating frequencies for the MPC885/MPC880 derivative devices.

Table 38. Available MPC885/MPC880 Packages/Frequencies

Package Type	Temperature (Tj)	Frequency (MHz)	Order Number
Plastic ball grid array ZP suffix — Leaded VR suffix — Lead-Free are available as needed	0°C to 95°C	66	KMPC885ZP66 KMPC880ZP66 MPC885ZP66 MPC880ZP66
		80	KMPC885ZP80 KMPC880ZP80 MPC885ZP80 MPC880ZP80
		133	KMPC885ZP133 KMPC880ZP133 MPC885ZP133 MPC880ZP133
Plastic ball grid array CZP suffix — Leaded CVR suffix — Lead-Free are available as needed	-40°C to 100°C	66	KMPC885CZP66 KMPC880CZP66 MPC885CZP66 MPC880CZP66
		133	KMPC885CZP133 KMPC880CZP133 MPC885CZP133 MPC880CZP133

16.1 Pin Assignments

Figure 77 shows the top-view pinout of the PBGA package. For additional information, see the *MPC885 PowerQUICC™ Family Reference Manual*.

NOTE: This is the top view of the device.

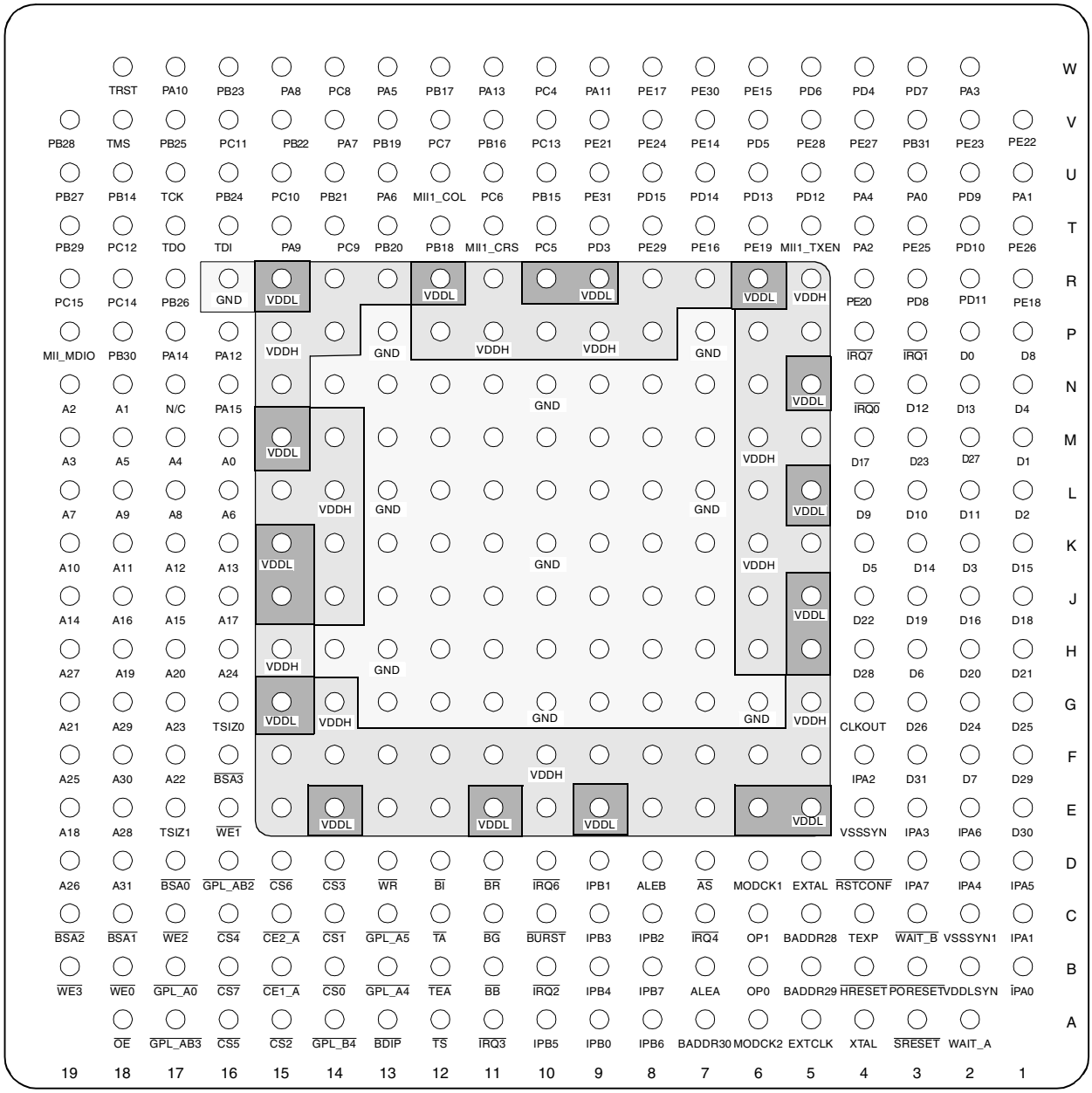
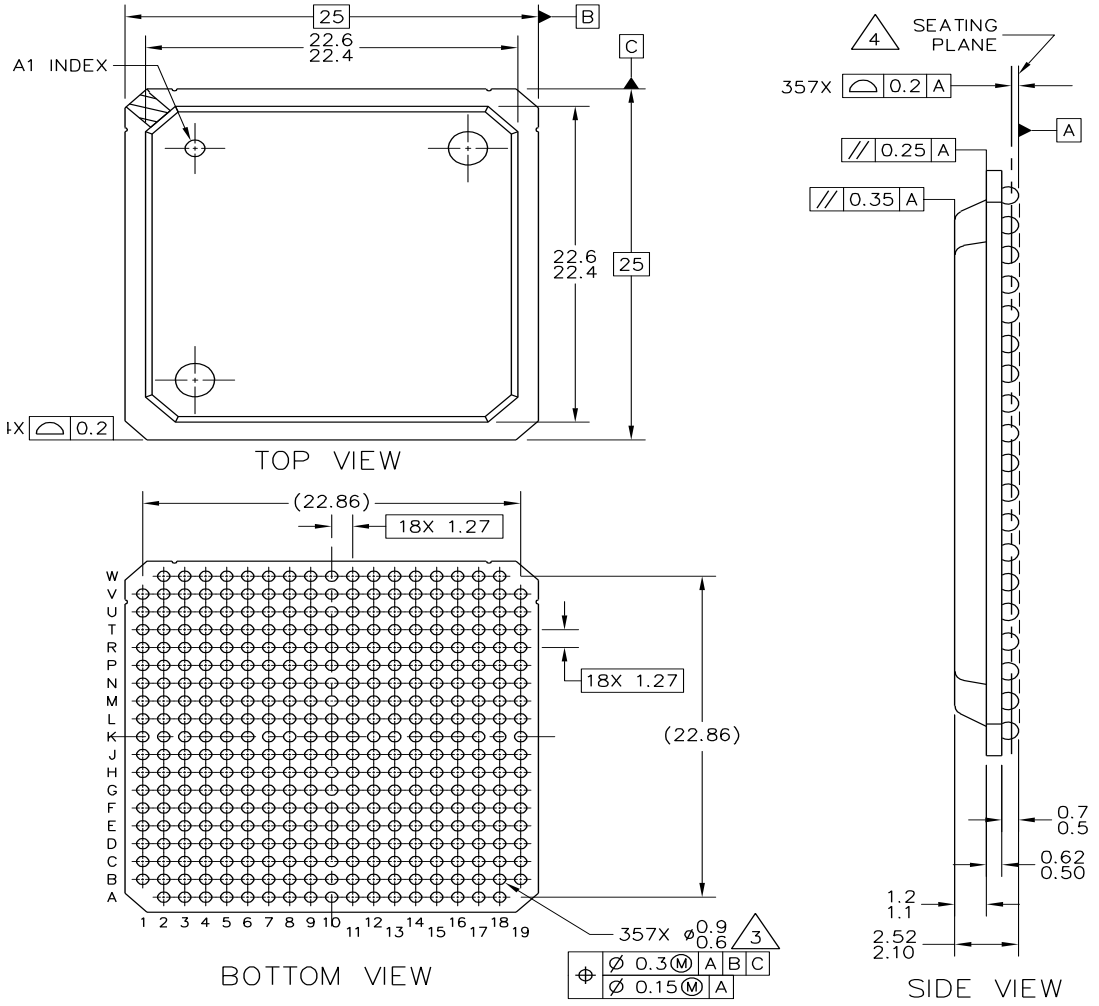


Figure 77. Pinout of the PBGA Package

16.2 Mechanical Dimensions of the PBGA Package

Figure 78 shows the mechanical dimensions of the PBGA package.



NOTES:

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M—1994.
3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM A.
4. DATUM A, THE SEATING PLANE, IS DEFINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

Figure 78. Mechanical Dimensions and Bottom Surface Nomenclature of the PBGA Package

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